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BT		4,592,081	05/27/1986	Eaton e	t al.			IF APPROPE	RIATE
		4,211,489	07/08/1980	Kleinkn	echt et al.	· · · · · · · · · · · · · · · · · · ·			
		2,302,024	11/17/1942	Goss, Jr					
		3,742,229	06/26/1973	Smith et	t al.				-
		3,951,548	04/20/1976	Westell					
		4,037,325	07/26/1977	Weber e	et al.				
		4,200,395	04/29/1980	Smith et	t al.		ï.		
		4,475,223	10/02/1984	Tanigue	chi et al				
					y et al.				
V		4,883,563 11/28/1989 Kot			et al.				
BT		6,056,526	05/02/00	Sato					
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13-5		1196749	01/30/1988	Japan w	/English Abstract				
		244884	03/28/1986	Europea	an				
V		4255307	09/10/1992	Japan w	/English Abstract				
bT		4332694	08/05/1991	Japan w	/English Abstract				
		OTHER DOCUMEN		•	Title, Date, Pertinent P				
Kt	Broers, et al., "250-A Linewidths with PMMA Electron Resist", <u>Applied Physics Letter 33 (5)</u> , 1978 American Institute of Physics, 392-394, (September 1, 1978)								
135		Chou, S.Y., et al., "Impri	int Lithography	with 25-N	anometer Resolution", <u>Scie</u>	nce, Vol. 277	2 <u>,</u> 85-87, (April	5, 1996)	
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155	5,352,394	10/04/1994	Fujita e	et al.		T		
	3,743,842	07/03/1973	Smith,	H.I., et al.				
	4,310,743	01/12/1982	Seliger,	, R.L.				
	4,383,026	05/10/1983	Hall, T.	.М.				
	4,450,358	05/22/1984	Reynole	ds, G.O.				
T	4,498,009	02/05/1985	Reynol	ds, G.O.				
	4,516,253	05/07/1985	Novak,	W.T.				
	4,552,615	11/12/1985	Amendo	ola, A., et al.				
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y	4,606,788	08/19/1986	Moran,	P.L.				
131	4,731,155	03/15/1988	Napoli,	L.S., et al.				
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BT	9117565	11/14/1991	PCT					
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135	WO 93/21671	10/28/1993	PCT					
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BI	Fischer, et al., "10 nm E Microscope", <u>Applied P</u>	lectron Beam Lit hysics Letter 62 (hography (23), 1993	and sub-50 nm Overlay Us American Institute of Physi	ing a Modifi ics, 2989-299	led Scanning El 91 (June 7, 1993	ectron 3)	
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145		3,833,303	09/03/1974	Burns e	et al.				
		4,325,779	04/20/1982	Rossett	i, J.J.				
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		5,277,749	01/11/1994	Griffith	h, J.H., et al.				
		5,861,113	01/19/1999	Choque	ette, S.J., et al.				
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		5,152,861	10/06/1992	Hann					
					mikia				
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1		5,234,571	08/10/1993	Noeker					
35		4,738,010	04/19/1988	Ehrfeld	et al.				
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137	Harmening, et al., "Molding of Threedimensional Microstructures by the Liga Process" Proceedings IEEE: Micro Electro Mechanical Systems, Travemunde, Germany, 202-207, (1992)							lectro	

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		4,788,015	11/29/1988	Sakai et	t al.				
		4,294,650	10/13/1981	Werthm	nann				
		3,923,566	12/02/1975	Law					
		5,259,926	11/09/1993	Kuwaba	ara et al.				
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		5,503,963	04/02/1996	Bifano					
		4,543,225	09/24/1985	Beaujea	in				
V		5,434,107	07/18/1995	Paranjp	je				
35		5,338,396	08/16/1994	Abdala	et al.				
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HT		Nomura, et al., "Moire A (1), American Vacuum Se	lignment Techni ociety, 394-398, (que for the Jan/Feb 1	e Mix and Match Lithogra 1988)	phic System:	J. Vacuum Soo	ciety Techn	<u>iol. B6</u>
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by	5,471,455	05/17/1994	Jabr						
	4,287,235	05/29/1979	Flander	s ·					
1	4,512,848	04/23/1985	Deckma	n et al.					
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15	Kamins, T.I., et al. Physics Letter, Vol	, "Positioning of Self-A . 74, No. 12, March 22	ssembled, , 1999.	single-crystal,germanium i	slands by si	licon nanoimpr	inting" Ap	plied	
155	Wang, J., et al., "Fabrication of a new broadband waveguide polarizer with a double-layer 190 nm period metal-gratings using nanoimprint lithography" J. Vac. Sc. Technol. B 17 (6) Nov/Dec 1999.								
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155	Feynman, Richard, "There's Plenty of Room at the Bottom-An Invitation to Enter a New Field of Physics" talk delivered at the annual meeting of the American Physical SOciety at the California Institute of Technology (Caltech) in 1959, published in February 1960 issue of Caltech's "Engineering and Science".									
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M		Vacuum Society	, USA.		•	widths using z-ray ma 979 (received 11 June						
GT	Jorritsma et al., "Fabrication of large arrays of metallic nanowires on V-grooved substrates" Applied Physics Letters 67 (10), 4 September 1995 (received 16 May 1995), pp. 1489-1491, published by American Institute of Physics, USA.											
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	Nisper, "Injection-mold	ed replication if bina	ary optic structures", SPIE v260	0 Oct 23-24, 1	995 p. 56-64 02	27-786X		
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45	Shvartsman, "Holograph	ic optical elements b	y dry photopolymer embossin	g" SPIE (1991)	1461 (pract. H	olog. S) pp. 313	-320
145	"Fabrication of submicro Vol. 1, No. 4, Dec 1983 p	on crossed square wa p. 1207-1210	ive gratings by dry etching and		replication tec	hniques'' JVST	В
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